

FORM PTO-1449
REV. 7.80 U.S. Department of Commerce
PATENT AND TRADEMARK OFFICEAttorney Docket No.:
15.55/6364Serial No.:
10/050,793

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant:
EBINAFiling Date:
Jan. 18, 2002Group:
2815

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date if Appropriate
TD	5 2 4 0 8 6 5	31Aug93	Malhi			
TD	6 2 4 6 1 0 4	12Jun01	Tsuda et al.			
TD	5 9 9 8 8 5 4	7Dec99	Morishita et al.			
TD	2002/ 01 3 0 4 0 9	7Feb02	Oue et al.			
TD	5 4 5 9 0 8 3	17Oct95	Subrahmanyam et al.			
TD	5 5 5 2 6 2 4	3Sep96	Skotnicki et al.			
TD	6 2 2 5 6 6 4	1May01	Endo et al.			
TD	6 2 3 2 6 4 9	15May01	Lee			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub-Class	Translation	
						Yes	No
TD	62- 1 2 8 5 6 1	10Jun87	Japan			abst.	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

TD	Notice of Reasons of Rejection for Japanese Patent Application No. 2001-011858 (from which priority is claimed in U.S. Serial No. 10/050,792), which cites JP05-041488 and JP05-218316, which were previously cited in an IDS.
TD	Notice of Reasons of Rejection for Japanese Patent Application No. 2000-382395 (from which priority is claimed in U.S. Serial No. 10/014,612), which cites JP05-041488 and JP05-218316, which were previously cited in an IDS.
TD	Parke et al., "Bipolar-FET Hybrid-Mode Operation of Quarter-Micrometer SOI MOSFET's," <i>IEEE Electron Device Letters</i> , Vol. 14, No. 5, May 1993, pp. 234-236.

Examiner

Date Considered 11/18/03

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.